规格书编号

SPEC NO :

产品规格书
SPECIFICATION

CUSTOMER 客 户：

PRODUCT 产 品：SAW FILTER

MODEL NO 型 号：HDF315MT039

PREPARED 编 制： CHECKED 审 核：

APPROVED 批 准： D A T E 日 期：2006-5-11

客户确认 CUSTOMER RECEIVED:		
审核 CHECKED	批准 APPROVED	日期 DATE

无锡市好达电子有限公司

Shoulder Electronics Limited

更改历史记录
History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark

1. SCOPE

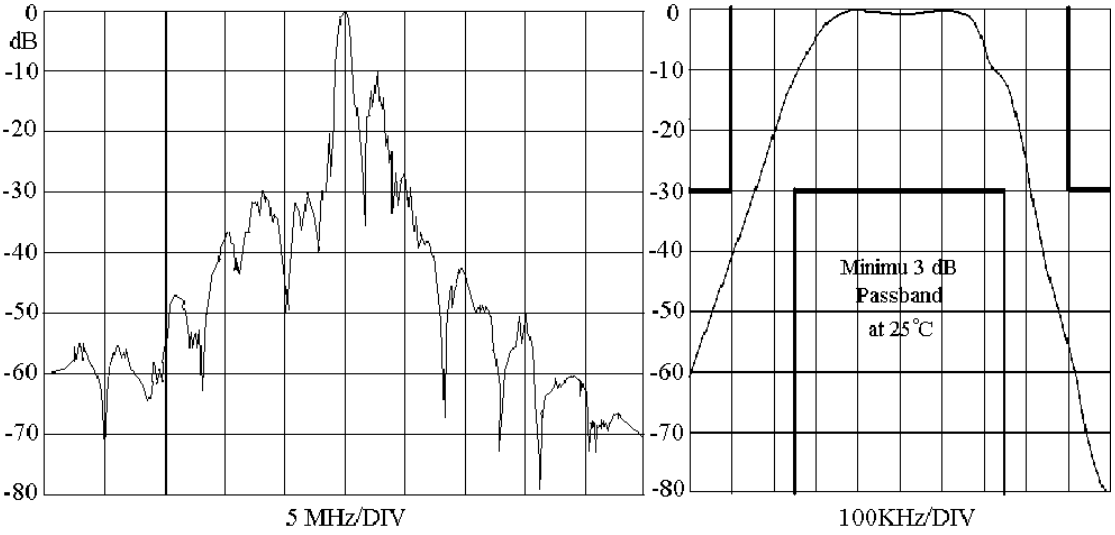
This specification shall cover the characteristics of SAW filter 315MHz with used for remote-control security.

2. ELECTRICAL SPECIFICATION

DC Voltage VDC	10V
AC Voltage Vpp	10V50Hz/60Hz
Operation temperature	-40℃ to +85℃
Storage temperature	-45℃ to +85℃
Max Input Power	10dBm

Electronic Characteristics

2-1.Type frequency response



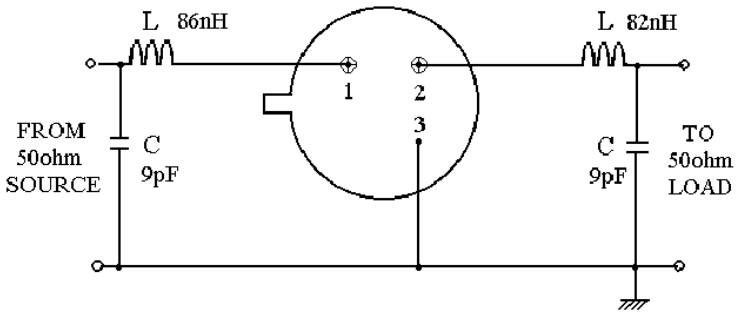
2-2.Electrical characteristics

Characteristic		Sym	Notes	Min	Typical	Max	Units
Center frequency	Absolute frequency	Fc	1.2	314.920	315.000	315.080	MHz
	Tolerance from nominal	Δ fc				±80	KHz
Insertion Loss		IL	1		1.7	3.0	dB
3dB Bandwidth		BW_3	1.2	500	700	800	KHz
Passband Ripple (Fc±400 KHz)					0.2	0.5	dB
Rejection	At fo-21.4MHz (Image)		1	40	50		dB
	At fo-10.7 MHz (LO)			16	40		
	Ultimate				80		
Temperature characteristics	Operating case temp.	Tc	3.4	-35		+85	℃
	Tumor temp.	To		22	37	62	℃
	Tumover Frequency	fo			fc		MHz
	Fre.temp.coeficient	FTC			0.032		ppm/℃
Frequency aging			5		<±10		ppm/y

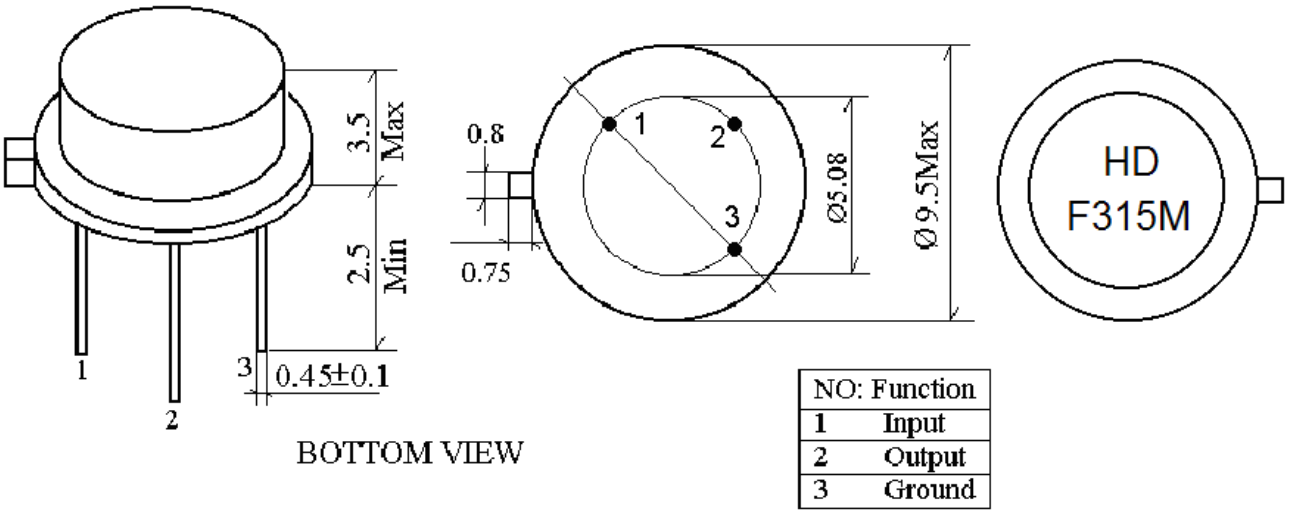
Note:

1. Typical test circuit is shown as below.
2. Passband and reject bands are specified in reference to fc.
3. The turnover temperature, To, is the temperature at the maximum frequency, Fo.
4. The nominal frequency at any case temperature, Tc, inside the operating temperature range may be calculated from:$f=fo[1-FTC(To-Tc)^2]$.
5. Typical aging is for 10 years.

3. TEST CIRCUIT



4. DIMENSION



NO:	Function
1	Input
2	Output
3	Ground

5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to +85℃ for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

5-2 Low temperature exposure

Subject the device to -40℃ for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

5-3 Temperature cycling

Subject the device to a low temperature of -40℃ for 30 minutes. Following by a high temperature of +85℃ for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2-2.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at 260℃ ±10℃ for 10±1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2-2.

5-5 Solderability

Subject the device terminals into the solder bath at 245℃ ±5℃ for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2-2.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2-2.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2-2.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration &destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be solded. Please avoid soldering another part of component.